# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

## Precision Technologies, Inc.

**1740 State Route 61**
**Crestline, OH 44827**

Fulfills the requirements of

## ISO/IEC 17025:2017

In the fields of

## CALIBRATION and DIMENSIONAL MEASUREMENT

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 16 April 2024
Certificate Number: L2006-1

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

# SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

**Precision Technologies, Inc.**
1740 State Route 61
Crestline, OH 44827
Chris Brickner
419-683-8029

## CALIBRATION AND DIMENSIONAL MEASUREMENT

Valid to: **April 16, 2024** Certificate Number: **L2006-1**

## CALIBRATION

**Length – Dimensional Metrology**

| Parameter/Equipment | Range | Expanded Uncertainty of Measurement (+/-) [1] | Reference Standard, Method, and/or Equipment |
|---|---|---|---|
| Calipers (0.000 5 resolution) | (0 to 12) in | (420 + 4.7*L*) µin | Gage Blocks |
| Calipers (0.001 resolution) | (0 to 12) in | (580 + 0.6*L*) µin | Gage Blocks |
| Depth Micrometers | (0 to 12) in | (590 + 0.5*L*) µin | Gage Blocks |
| OD Micrometers | (0 to 12) in | (650 + 16.8*L*) µin | Gage Blocks |
| Dial Indicators | (0 to 0.5) in | (630 + 25.1*L*) µin | Gage Blocks |
| Digital Indicator | (0 to 1) in | (55 + 30.1*L*) µin | Gage Blocks |
| Micrometer Standards, Length Rods | Up to 20 in | (20 + 4.7*L*) µin | Helios w/Ref Block |
| Thread Plugs<br>Major Diameter<br>Pitch Diameter | Up to 2.4 in | <br>134 µin<br>144 µin | Helios w Thread Wires |
| Pin Gages | Up to 1 in | 20 µin | Helios |
| Ring Gages | Up to 4 in | (41 + 26*L*) µin | Helios |

# DIMENSIONAL MEASUREMENT

**3 Dimensional**

| Parameter/Equipment | Range | Expanded Uncertainty of Measurement (+/-) [1] | Reference Standard, Method, and/or Equipment |
|---|---|---|---|
| Dimensional Measurement 3D | X = (0 to 60) in<br>Y = (0 to 125) in<br>Z = (0 to 50) in | (380 + 39*L*) µin | CMM with Probe |
| | X = (0 to 27.5) in<br>Y = (0 to 39.5) in<br>Z = (0 to 20.5) in | (380 + 37*L*) µin | |

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k$=2), corresponding to a confidence level of approximately 95%.

Notes:

1. $L$ = length in inches.
2. This scope is formatted as part of a single document including Certificate of Accreditation No. L2006-1.

R. Douglas Leonard Jr., VP, PILR SBU